

introducing the new WinCamD™-LCM CMOS beam profiler



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MEDIA

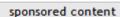
TEST, MEASUREMENT & POSITIONING

LIGHT EXCHANGE

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1" CMOS Beam Profiler with SuperSpeed USB 3.0

DataRay's new WinCamD-LCM CMOS Beam Profiler provides SuperSpeed USB 3.0 transfer rates and a high-resolution 1" CMOS detector. This 4.2 MPixel beam profiling camera features 5.5 μ m pixels, a 2048 imes 2048 active area, an update rate of up to 30 Hz, and an optical/TTL trigger. The advanced CMOS detector eliminates comet tailing, and the global shutter with trigger enables pulse capture. DataRay's full-featured, intuitive software is included with every system.

Download the Datasheet >>





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Liquid Crystal Matrix Slows Light to 1 Billionth of its Speed

Light can be slowed to less than a billionth of its top speed by using embedded dye molecules in a liquid crystal matrix, which could lead to new technologies in remote sensing and measurement science.

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Squeezed Light Created On-Chip

A microchip-based way to create squeezed light could assist a range of precision metrology applications by providing a viable route toward real-world on-chip sensors and technology.

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Photodetector Discerns Polarized Light Intrinsically

Few photodetector materials can discern polarized light - individual electromagnetic waves oscillating parallel to one another - directly without the use of a grate or a filter. For a newly created carbon-based broadband photodetector, however, polarimetry is intrinsic to the active material.

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Real-time Profiling for Focusing, M2, Divergence &

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Real-time Profiling for Focusing, M2, Divergence & Alignment

Beam intensity profiling is an essential tool in many aspects of photonics. The precise intensity distribution in a focused laser beam is critical in many applications: flow cytometry, laser printing, medical lasers, and cutting lasers are just a few examples. Intensity profile measurements can characterize and improve a product or process, leading to substantial cost and time savings that can pay for the measurement instrument many times over. This white paper describes how the unique, patented, real-time multiple z-plane XYZTF capabilities of the BeamMap2 slit-scan profiler can speed and simplify laser assembly alignment.

Download White Paper >>

FEL pulse temporal profile made in a FLASH

The temporal profile of an individual free-electron laser (FEL) pulse now can be measured with femtosecond precision using FLASH, a soft-x-ray FEL. The technique could be used to film atoms in motion or to study chemical reactions and phase transitions.

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Power measurement could speed solar innovation

An automated system that quickly measures the electric power output of solar devices could help researchers and manufacturers develop next-generation solar cells.

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